## Claims

## What is claimed is:

- 1. A chip sorting method, comprising the steps of;
- 5 (a) having a wafer on the first platform, said wafer at least comprises a chip;
  - (b) lifting up a positioning axis of said first platform to withstand said chip;
  - (c) using a probe of said robotic arm to inspect said chip; and
- (d) using a second robotic arm to suck said chip, and to place it to thesecond platform.
  - 2. The method according to claim 1, wherein said second platform at least comprises a specialized bin.
  - 3. The method according to claim 1, wherein said test can include an electricity test for inspecting the said chip.
- 4. The method according to claim 2, wherein said step(d) further includes the test following step(c), and it places the chip to said pre-sorting specialized bin.
  - 5. The method according to claim 1, wherein said step(a) further includes pre-cutting said wafer for dividing said chip.
- 20 6. The method according to claim 1, wherein said step(a) further includes said wafer processing the chipping on the blue film after cutting.
  - 7. A chip sorting apparatus, comprising;
- a first platform providing a place for wafer, and said wafer at least including a chip;
  - a positioning axis setting under the first platform, and having a withstand-end for lift and down;

- a first robotic arm having a probe;
- a second robotic arm having a sucking mechanism; and
- a second platform providing the place for said chip;
- wherein said withstand-end can use lift-down to withstand said chip, It
- uses said probe to inspect the said chip, and then, it uses said
  - sucking mechanism to suck the chip, and places it to said second
  - platform.

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- 8. The apparatus according to claim 7, wherein said second platform at least includes a specialized bin.
- 9. The apparatus according to claim 7, wherein said test can include an electric test for inspecting said chip.
  - 10. The apparatus according to claim 8, wherein it can rely on the test of said probe, and place the chip to said pre-sorting specialized bin.
  - 11. The apparatus according to claim 7, wherein said wafer is positioned on said first platform and is pre-cut for dividing said chip.
  - 12. The apparatus according to claim 11, wherein said wafer setting in the said platform, and said wafer is positioned on the blue film and processes a chipping after being cut.